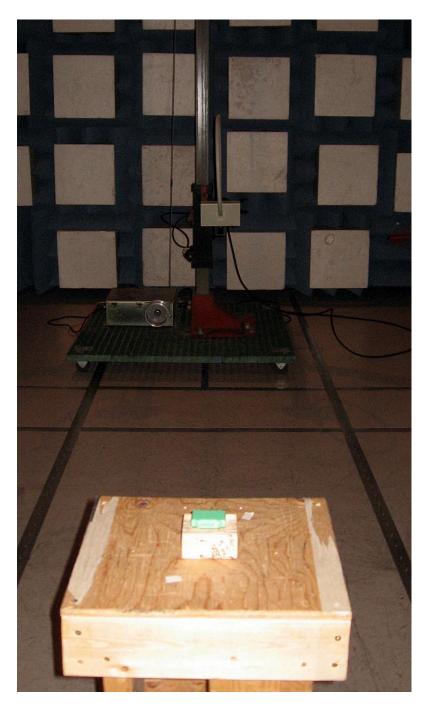
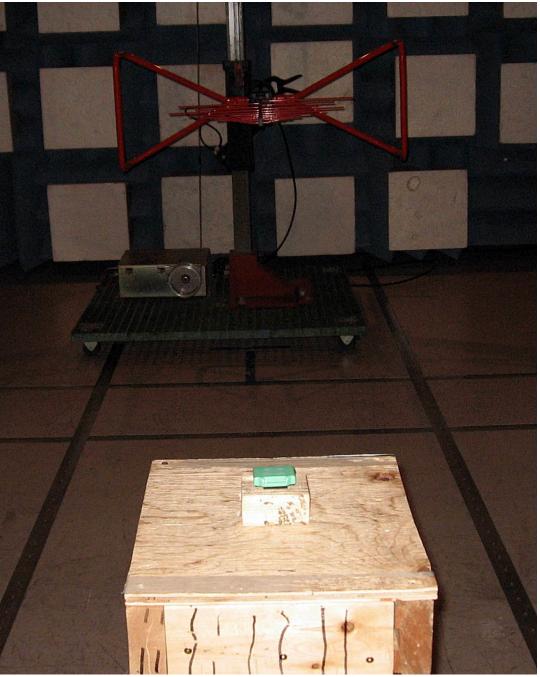
Test setup

- Test configuration for LF Testing,125kHz to 30MHz



Prepared by: Date Issued: Project No: LabTest Certification Inc. 17 August, 2016 13591 Client: Report No.: Revision No.: Guard RFID Solutions Inc. 13591-1E 0

- Test configuration for Radiated Emission, 30 MHz to 1GHz



Page 2 of 4

This document shall not be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from LabTest Certification Inc.

Prepared by:LabTest Certification Inc.Date Issued:17 August, 2016Project No:13591

Client: Report No.: Revision No.: Guard RFID Solutions Inc. 13591-1E 0

-Test setup on Table, Orthogonal X



-Test setup on Table, Orthogonal Z



-Test setup on Table, Orthogonal Y

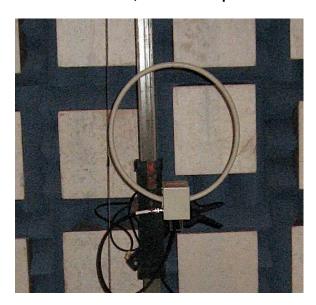


Page 3 of 4

This document shall not be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from LabTest Certification Inc.

Prepared by:LabTest Certification Inc.Date Issued:17 August, 2016Project No:13591

- Antenna Position; H & Mainloop



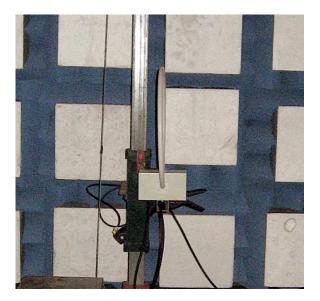
- Antenna Position; V & Mainloop

- Antenna Position; H & Sideloop

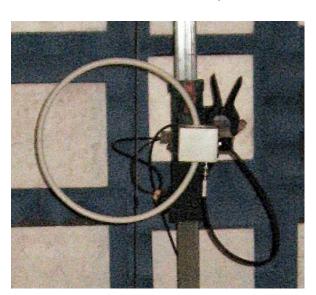
Client:

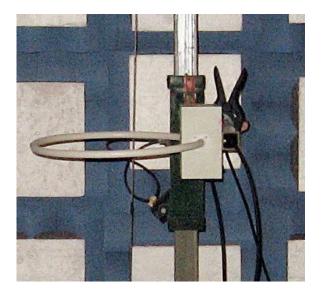
Report No.:

Revision No.:



- Antenna Position; V & Sideloop





Page 4 of 4

This document shall not be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from LabTest Certification Inc.